27948 S/185/60/005/004/007/021 D274/D306

Effect of the external electric ...

for a single surface state only. As the germanium and silicon surfaces have 4 fast states, it is of interest to generalize Johnson's formula for any number of states.  $V_D^{\rm S}$  is determined from

$$V_{\rm p}^{\rm s} = \frac{{\rm k'}\Gamma}{{\rm e}} \, \Delta \, {\rm Y} \approx \frac{{\rm k'}\Gamma}{{\rm e}} \, \cdot \frac{{\rm d}{\rm Y}}{{\rm d}\Delta_{\rm p}} \, \Delta_{\rm p} \,,$$
 (2)

where  $\Delta_{\rm D}$  is the relative increase in hole-concentration during illumination of the specimen. After some transformations one obtains

 $\frac{dY}{d\Delta_p} = \frac{\lambda \left(e^Y + e^{-Y} - 2\right) + \sum_j \beta_j \Phi_j}{\left(\lambda e^{-Y} - \lambda^{-1} e^Y + \lambda^{-1} - \lambda\right) + \sum_j \Phi_j},\tag{11}$ 

where

 $\beta = \left\{ \begin{array}{l} +1 & \text{при } T_j \gg 1 \\ -\lambda^2 & \text{при } T_j \ll 1 \end{array} \right\},$   $\Phi_j = -\frac{2FN_j}{n_j L} \left\{ 1 + e^{-(Y - \ln \lambda + \gamma)} \right\}^{-2} e^{-(Y - \ln \lambda + \gamma)}.$ (12)

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<sup>27948</sup> S/185/60/005/004/007/021 D274/D306

Effect of the external electric ...

Formulas (2) and (11) determine the dependence of the photo-cmf  $V_D^S$  on the surface potential and surface states. Figures are shown with theoretical and experimental curves  $V_D^S(Y)$ . It is noted that the agreement between theory and experiment is good qualitatively the agreement between theory and experiment is good qualitatively only, whereas quantitatively there are discrepancies; these may only, whereas quantitatively there are discrepancies; these may only, whereas quantitatively there are discrepancies; these may only only of due to neglecting slow surface states, and to errors in determining the surface potential and surface states. Further, the drop is considered in the capacitor photo-emf which depends on  $\Delta_P$ . For silicon, the time constants  $\tau_P$  and  $\tau$  are not only of different magnitude (in the absence of an external field), but their dependence on Y is of a different character too. It is likely that the formation of a p-n junction at the silicon surface hinders the relaxation of the photo-emf. The magnitude of  $\tau_P$  is determined by diffusion processes and surface recombination. The surface conditions (zone buckling and surface states) have a considerable effect on the photo-emf of silicon and germanium. The surface potential Y can be determined in principle by comparing experimental and theoretical values of  $V_P(U)$  and  $V_P(Y)$ . But such

Card 6/8

Effect of the external electric.

279년8 S/185/60/005/004/007/021 D274/D306

ASSOCIATION:

Instytut fizyky AM USSR (Physics Institute AS UkrSSR)

SUBMITTED.

November 5, 1959

Card 8/8

APPROVED FOR RELEASE: 08/25/2000 CIA-RDP86-00513R001651810015-3"

89270

S/181/61/003/001/002/042 B102/B212

9.4300 (1043, 1143, 1155)

AUTHORS:

Primachenko, V. Ye. and Snitko, O. V.

TITLE:

The role of a dielectric in investigations of the field

effect in semiconductors

PERIODICAL:

Fizika tverdogo tela, v. 3, no. 1, 1961, 15-18

TEXT: One of the most important methods used to study the surface properties of semiconductors is the method of the field effect (change of the surface conductivity under the influence of an external electric field) here, the semiconductor is a capacitor plate which is covered with a dielectric (mica, strontium titanate) to increase the breakdown voltage. Therefore it is of interest to know the effect of the dielectric on the surface properties of the semiconductor; several studies made for this purpose (among others, by Shao and Morrison) are briefly discussed in the introduction. In the following, the authors report on their own experiments. First, they repeated the experiments of Shao and found that a considerable charge remains on the mica after the electrode has been removed unter voltage. Then, experiments have been undertaken to measure

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Card 1/5

89270 · S/181/61/003/001/002/042 B102/B212

The role of a dielectric in...

the field effect and the capacitor photo-e.m.f. directly, with and without mica, in a vacuum and in air. These experiments were made with n- and p-type Ge and n-type Si. As the results obtained were similar, only those concerning the n-type Ge ( = 28 ohm·cm, thickness 340  $\mu$ ) are discussed. Fig. 1 shows the change of the conductivity  $\Delta\sigma$  and the capacitor photo-e.m.f. V, measured for 15 seconds after a constant field had been applied, as a function of the capacitor charge (Q=CV); C with mica has 25 μμF, without mica, 10.5 μμF. Fig. 2 illustrates the long-period relaxation effect of the field for various cases. It is demonstrated again that curves recorded with and without mica coincide in dry air and in a vacuum, while those recorded in humid air deviate considerably from each other. Relaxation is more rapid with mica. All experiments showed consistently that in fields up to  $1-2\cdot 10^5$  v/cm, no charges are transferred from the semiconductor to the dielectric in dry air and in vacuo. Results obtained for humid air are indicative of a partial charge transfer to mica, which increases with humidity; this is related to the surface conductivity of mica in humid air. There are 2 figures and 9 references: 6 Soviet-bloc and 3 non-Soviet-bloc.

Card 2/5

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SMITKO, O., kand.fiz.-matem.nauk

Semiconductors. Nauka i zhyttia 11 no.3:25-27 Nr 162.
(MIRA 15:8)

(Semiconductors)

CIA-RDP86-00513R001651810015-3 14152 s/181/62/004/010/045/063 B102/B112 Primachenko, V. Ye., Litovchenko, V. G., Lyashenko, V. I., Minority carrier adhesion on the silicon surface and Snitko, O. V. Fizika tverdogo tela, v. 4, no. 10, 1962, 2925-2930 AUTHORS: TEXT: This paper is aimed to show that under certain conditions a TEAT: This paper is aimed to show that under certain conditions a charge accumulation may occur on the silicon surface and that the bigolarity (An An) may be disturbed which is however control bigolarity (An An) may be disturbed. charge accumulation may occur on the silicon surface and that the bipolarity  $(\Delta n = \Delta p)$  may be disturbed. This is, however, contradictory to the observations made by other suthers (see a g phys. Rev. 101. 1272). TITLE: bipolarity (An = Ap) may be disturbed. This is, nowever, contradictory to the observations made by other authors (see e.g. Phys.Rev.101, 1272, pho disturbance of bipolarity of the 1056. Serie Surf Phys. Ac 1957) PERIODICAL: to the observations made by other authors (see e.g. Phys.Rev.101, 1272, 1956; Semic.Surf.Phys., 85, 1957). The disturbance of bipolarity of the intrinsic photocorductivity observed is attributed to minority observed in attributed to minority observed. iyyo; Semic. Suri. rnys., 07, 1971). The disturbance of bipolarity of the intrinsic photoconductivity observed is attributed to minority carriers accumulating on fact surface levels. Intrinsic photoconductivity observed is attributed to minority carriers accumulating on fast surface levels. The same method of investigation accumulating on fast surface levels. accumulating on fast surface levels. The same method of investigation was used as described in previous papers (FTT 1,980,1959; FTT 2, 591, 1960: UF7h.5.3/5.1960). was used as described in previous papers (FTT 1,980,1979; FTT 2, 771, 980; UFZh,5,345,1960). The specimens were n-type Si single crystal The specimens were of 30 - 200 ohm.cm and volume platelets 200-400µ thick with resistivities of 30 - 200 ohm.cm and volume platelets 200-400µ thick with resistivities of which had been etched with CP-8. It fetimes of ~1000usec. platelets 200-400 $\mu$  thick with resistivities of 30 - 200 ohm.cm and volume platelets 200-400 $\mu$  thick with resistivities of which had been etched with CP-8. Lifetimes of  $\sim 1000 \mu sec$ , the surfaces of which had been etched with CP-8. In germanium the bipolarity of the surface photocurrent may be disturbed. card 1/3

s/181/62/004/010/045/063 B102/B112

only at low temperatures, but in etched silicon it may be disturbed even Minority carrier adhesion on ... only at low temperatures, out in evened 5111001 10 may be allowed at room temperature. This is proved (1) by the nature of the photoconductivity relaxation of thin samples if the oscillogram shows two conductivity relaxation of thin samples if the constant Tsh exponents with widely differing time constants; (2) by the constant Tsh of the short-term photocurrent component being inversely proportional to the electric field applied, whereas the constant of the long-term component is independent of it; (3) by the fact that the long-term component can be caused to vanish by the usual method of trap filling; (4) by the long-term component increasing as the temperature decreases, while the short-term component decreases and almost vanishes completely, this being related to the intensified charge accumulation; in both cases  $\ln \tau = f(1/T)$  follows a linear course; (5) by the results obtained in a study of the kinetics of the field effect also indicating a disturbance of bipolarity. This bipolarity is also indicated by the field dependence of  $\tau_{\rm sh}$  and  $\tau_{\rm l}$  and (7) it is particularly pronounced in samples kept on air for a longer period of time after they had been etched. (8) Experiments on the condenser photo-emf proved that the disturbance of the photocurrent on the condenser photo-emi proved that the disturbance of the photocurr bipolarity of Si is related to a change in the surface charge. Such a

Card 2/3

Minority carrier adhesion on ...

**S/181/62/004/010/045/063** B102/B112

disturbance occurs when  $\frac{C_n}{C_p} \exp \frac{E_{tv} - \mu_{nc}}{kT} \ll 1$  and  $\tau_c N_v C_p \exp(-E_{tv}/kT) \leqslant 1$ where  $C_{
m p}$  and  $C_{
m n}$  are the electron and hole trapping cross sections,  $E_{
m tv}$ the energy of the levels relative to the valence band,  $\mu_{\mbox{\scriptsize nc}}$  the electron Fermi quasilevel relative to the conduction band,  $\tau_{_{\mbox{\scriptsize C}}}$  the recombinative lifetime and N $_{_{f V}}$  the effective number of levels in the valence band. There are 3 figures.

ASSOCIATION: Institut poluprovodnikov AN USSR, Kiyev (Institute of Semiconductors AS UkrSSR, Kiyev)

SUBMITTED:

February 6, 1962 (initially) June 12, 1962 (after revision).

Card 3/3

APPROVED FOR RELEASE: 08/25/2000

CIA-RDP86-00513R001651810015-3"

NESTERENKO, B.A.; PASECHNIK, Yu.A.; SNITKO, O.V.; FROLOV, O.S.

Field effect in thin lead sulfide films. Fiz. tver. tela 5 no.11: 3199-3206 N '63. (MIRA 16:12)

1. Institut poluprovodnikov AN UkrSSR, Kiyev.

BONDARENKO, V.N. [Bondarenko, V.M.]; ZHINDULIS, A.I. [Zhyndulis, A.I.]; LITOVCHENKO, V.G. [Lytovchenko, V.H.]; SNITKO, O.V.; FROLOV, O.S.

Effect of an external electric field on the work function of thin lead sulfide films. Ukr. fiz. zhur. 8 no.10:1110-1116 0 '63. (MIRA 17:1)

1. Institut poluprovodnikov AN UkrSSR, Kiyev.

IJP(c)/SSD/AEDC(a)/ESD(gs)/AFWL/ESD(t)/RAEM(t) JI S/0181/64/006/010/2913/2920 EWT(m)/EWP(b)-10373=65 ---AP4046597 ACCESSION NR: AUTHORS: Nesterenko, B. A.; Snitko, O. V. Investigation of atomically clean surfaces of germanium SOURCE: Fizika tverdogo tela, v. 6, no. 10, 1964, 2913-2920 TOPIC TAGS: germanium, surface condition, surface conductivity, recombination, oxidation, surface potential, capture cross section ABSTRACT: The surface conductivity, the field-effect kinetics and the generation-recombination noise of atomically clean and oxidized surfaces were investigated. The samples were rectangular slabs cut along the (111) plane from single-crystal p-type germanium (15 ohm.cm resistivity and 60 µsec volume lifetime), and etched in CP-8. The atomically clean surface was obtained by helium-ion bombardment followed by heating to 700°C in  $10^{-9}$  mm Hg vacuum. The oxidation was carried out in 5 x  $10^{-4}$  mm Hg vacuum for several tens of hours. The

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with a 20 µs valence band to a consider surface reduced orders of manda in the but increased noise was duthermal exchanged the study of the gating the known parameters.	ec time cons  This made  rable p-type  ced the dens  gnitude and  15 kc fre  d by several  te to fluctual  ange between  l/f <sup>2</sup> -type n  cinetics of s  cers of the t	density (≈10 <sup>14</sup> ) thank for the electron the surface hole surface conducts of these far produced slow surface of magnitudes in the surface according may be a conducted surface levels with the surface of general for hole consists. 7 figures and the surface contact of the surface of general for hole consists.	les degenerate ivity. The est surface levels is low for the itude on oxiderface hole deceptor levels onvenient metith short time manium surface pture, etc.)	e and gave rise exidation of the vels by several . The l/f²-typ clean surface ation. The maity due to . Therefore a hod of investie constants.	e :e
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2	ACCESSION NR: AP4046597	
	of Semiconductors, AN UkrSSR)	
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SSD/AFWL/ESD(gs)/IJP(c) WH/JD Pq-4 EWT(m)/EWP(b)/EWP(e)/EWP(t) S/0109/64/009/005/0876/0881 L 20501-65 ACCESSION NR: AP40 38648 ATHOA: Bondarenko, V. N.; Litvinova, E. M.; Snitko, O. V.; Tkhorik, Yu. A TLE: Effect of some coatings and thermal treatment of the surface r. ombination rate of silicon and germanium SOURCE: Radiotekhnika i elektronika, v. 9, no. 5, 1964, 876-881 TOPIC TAGS: silicon, metal coated silicon, germanium, metal coated germanium, surface recombination, surface recombination rate ABSTRACT: An experimental investigation of the effects of (1) low-temperature annealing of Si and Ge in He atmosphere and in contact with low-melt inorganic glasses and (2) coating Si and Ge with a very thin film of Au or Al upon the surface recombination rate (s) is reported. Single-crystal, 0.4-0.7-mm thick, Si and Ge plates were tested. Four types of glass were used: (1) Tl2Se As2Se3 (with a softening temperature of 109C),  $As_2Se_3 + I_{1.5}$  (85C),  $As_2Se_3 + I_2$  (70C). Card 1/2

L 20501-65

ACCESSION NR: AP4038648

and Tl<sub>2</sub>S. 2As<sub>2</sub>S<sub>3</sub>. It is found that annealing of n- or p-type Ge results in an increase of s by 2-3 times; a subsequent contact with glass results in an overall subsequent glass treatment, s was reduced to about 300 cm/sec. The same value of s was obtained by a vacuum-spraying of n-Si by gold (0.1-0.2 micron thick). The preliminary results of Al spraying were negative. "The authors wish to thank B. T. Kolomiyets and V. P. Shilo for lending the glasses." Orig. art.

ASSOCIATION: Institut poluprovodnikov AN UkrSSR (Institute of Semiconductors)

SUBMITTED: 22Mar63

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NO REF SOV: 006

OTHER: 004

Card 2/2

L 31017-65 EWT(1)/EWT(m)/EWP(t)/T/EWP(b)/EWA(h) Pz-6/Peb IJP(c) JD/AT

ACCESSION NR: AP5004321

5/0185/65/010/001/0039/0046

AUTHOR: Prymachenko, V. Ye. (Primachenko, V. Ye); Milenin, V.V.; Snitko, O.V.

TITLE: Investigation of gold-doped silicon surface

SOURCE: Ukrayins'kyy fizychnyy zhurnal, v. 10, no. 1, 1965, 39-46

TOPIC TAGS: silicon, surface state, doping, surface recombination, recombination rate, photo efm

ABSTRACT: The method of single high-voltage pulses was used to investigate the field effect of 20 p-type silicon samples etched and doped with gold from the etching substance. The samples had an approximate resistivity 3500 ohm-cm and a non-equilibrium volume carrier lifetime 700 microseconds. The orientation of the investigated surface was (111). The method of etching and electrode deposition is described. Measurments were made of the conductivity, photoconductivity, and capacitive photoemf as functions of the external electrical field applied to the sample surface through a mica plate. The experimental set-up for measuring the field effect is shown in Fig. 1 of the Enclosure. The photoconductivity and

Card 1/4

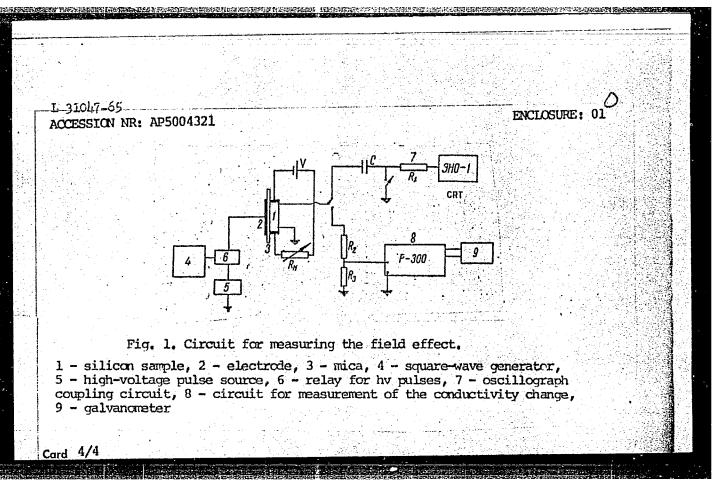
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ACCESSION NR: AP5004321

capacitive photoemf were measured by applying rectangular pulses of white light with fronts up to 5 x 10-7 sec, produced by a rotating mirror. Details of the sample preparation and of the experimental procedure were described by one of the authors elsewhere (Snitko, with G. V. Litovchenko, FTT v. 2, 591 and 815, 1960). The measurements were made at 20C, with the temperature maintained constant with an ultrathermostat. By comparing the experimental results with the theory, the authors determined the parameters of the surface states on doped and undoped surfaces. The presence of 1 x 10-6 -- 1 x 10-3% of gold in the etchant gives rise to an additional system of fast surface states, and also influences the parameters of the slow states. The most effective recombination level produced by the gold on the silicon surface lies 0.222 eV below the center of the forbidden band. This level is of the donor type ( $C_n = 6 \times 10^{-15}$  cm<sup>2</sup>, hole concentration 1 x 10<sup>-22</sup> cm<sup>2</sup>), and the concentration of the level depends on the content of gold in the etchant, lying in the range (0.8 == 4) x 10<sup>12</sup> cm<sup>-3</sup>. To obtain small surface-recombination rates in silicon it is necessary to employ extremely pure reagents and to treat the surface in a way that precludes the introduction of harmful impurities. "The authors thank N. A. Petrov for help with etching the samples." Orig. art. has: 6 figures.

Card 2/4

L 31047-65 ACCESSION NR: AP5004321 ASSOCIATION: Instytut napiv UkrSSR), Kiev	providnykiv	AN UkrSSR <b>(I</b> nstit	oute of Semiconducte	
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EWT(1)/EWT(m)/EWP(t)/T/EEC(b)-2/EWP(b) IJP(c) JD/GG L 31050-65 8/0185/65/010/001/0047/0054 AP5004322 ACCESSION NR: Nesterenko, B.O. (Nesterenko, B.A.); Pasichnyk, Yu. A. (Pasechnik. Yu.A.) Snitko, O.V.; Frolov, O.S. TITLE: Investigation of the influence of an external electric field on the photoconductivity and noise of thin layers of lead sulfide SOURCE: Ukrayins'kyy fizychnyy zhurnal, v. 10, no. 1, 1965, 47-54 TOPIC TAGS: lead sulfide, photoconductivity, noise voltage, dark conductivity, field effect ABSTRACT: The authors studied the influence of surface factors (external electric field, adsorption of molecules) on the photoconductivity and low-frequency noise of thin lead-sulfide layers. Measurements were made of the dark conductivity, the stationary photoconductivity, the photoconductivity time constant, and the noise amplitude at 400 cps, on chemically and physically prepared PbS layers, as functions of the external electric field, the surrounding gas atmosphere, and low-temperature heating. The test set-up for the conductivity noise amplitude is illustrated in Fig. 1 of the Enclosure. The bulk of the measurements were made in Card 1/4

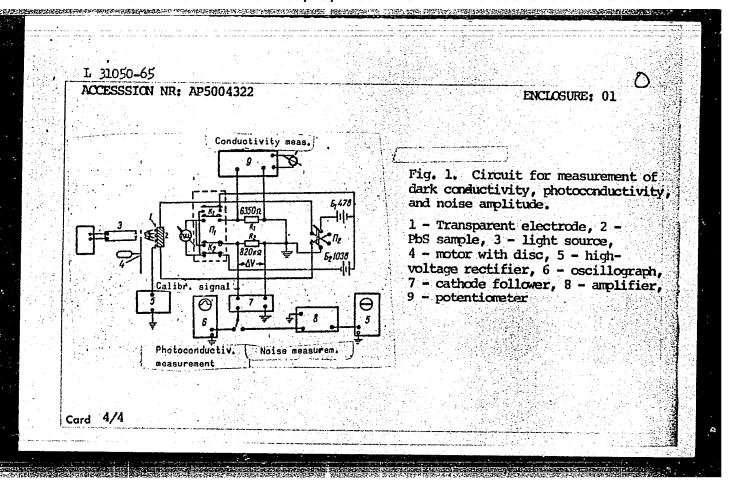
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ACCESSION NR: AP5004322

vacuum (1 x 10-6 mm Hg) and in dry air. The results have shown that physically and chemically deposited layers behave differently. Chemical layers had a conductivity relaxation that decreased with time following application of an external electric field, and exhibited appreciable influence of the external field on the photoconductivity and on the time constant. The physical layer showed a timeincreasing conductivity, and no effect of the external field whatever. The dependence of the photoconductivity of chemical layers on the external field usually had a maximum which varied with the sample. It is assumed that to the left of the maximum the decrease in photoconductivity is connected with the increased rate of surface recombination, and to the right of the maximum it is possibly due to a decrease in the effective mobility. Tests have shown that there is no difference in the properties of the external surface of chemical layers and the surface in contact with the substrate. An external electric field and the surrounding gas atmosphere exerts a noticeable influence on the noise amplitude at 400 cycles. The surrounding gas and heating to 1000 affect strongly the electrical parameters of chemical layers, with the most noticeable change taking place in the dark conductivity, which decreases in vacuum and also after heating in dry air. Some of the results are interpreted in light of earlier investigations by the authors.de-

Card 2/4

I 31050-65		
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wated to the effect of the	field on the dark conduct	ivity (FTT v. 5, 3199, 1963).
Orig. art. has: 7 figures,		
ASSOCIATION: Instytut napiv	providnykiv AN UkrSSR,Kie	(Institute of Semiconductors,
AN CAIBBRY		
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설계를 가는데 되면 그림이 되다		
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AUTHOR: Prymachenko, V. Ye. (Primachenko, V. Ye.); Snitko, O. V.: Milenin, V. V.

TITLE: Investigation of the non-equilibrium effect of depletion of majority carriers from silicon

SOURCE: Ukrayins'kyy fizychnyy zhurnal, v. 10, no. 4, 1965, 382-388

TOPIC TAGS: field effect, nonequilibrium effect, silicon, carrier depletion, conductivity modulation

ABSTRACT: The non-equilibrium field effect was investigated under the condition of intense depletion of majority carriers from silicon. The measurements were made at room and low temperatures (down to 170K) on p- and n-type samples measuring 1.2 x 0.5 x (0.02--0.05) cm. The samples were placed in a cryostat in which a vacuum of  $\sim 1 \times 10^{-6}$  mm Hg was maintained. A diagram of the measurement set-up is shown in Fig. 1 of the Enclosure. Two methods of attaining non-equilibrium depletion were used -- turning on depleting field and turning off enriching field. Appreciable modulation of the conductivity of the silicon plates was observed, reaching complete removal of the movable carriers from them. Under such conditions the conductivity of a thin silicon plate dropped practically to zero. The

Card 1/3

L 51445-65 ACCESSION NR: AP5011064

temperature dependence of the duration of such a state and of the half-life of the non-equilibrium field effect were investigated. A study was also made of the dependence of the duration of such a state and of the half-life on the applied voltage. Application of light exerts a noticeable influence on the non-equilibrium field effect. The results obtained demonstrate the possibility of employing the pulsed field effect in the depletion mode to obtain a non-equilibrium state without free carriers in the interior of a crystal at a depth on the order of several hundred microns (charged dielectric). At low temperature (-1200) this state exists for a relatively long time (tens of seconds) owing to the slowed down rate of thermal generation of surface charge, which does not have time to screen the external electric field in the pulsed depletion mode. A detailed discussion of the results on this basis of theoretical calculations are presented in a companion article (Accession Nr. AP5011065). Orig. art. has: 6 figures.

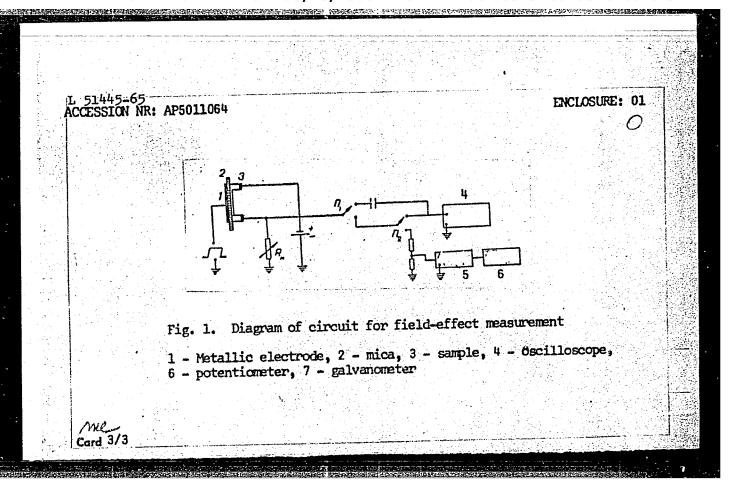
ASSOCIATION: Instytut napivprovidnykiv AN URSR, Kyyiv [Institut poluprovodnikov AN UkrSSR, Kiev ] (Institute of Semiconductors, AN UkrSSR)

SUBMITTED: 07Aug64 ENCL: 01 SUB CODE: 88

MR REF SOV:

OTHER:

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IJP(c) Pz-6/Peb EWT(1)/EWT(m)/T/EWP(t)/EWP(b)/EWA(h) JD/AT UR/0185/65/010/004/0389/0397 AP5011065 ACCESSION NR: AUTHOR: Prymachenko, V. Ye. (Primachenko, V. Ye.); Snitko, O. V.; Milenin, V. V. TITIE: Concerning the mechanism of the non-equilibrium effect of depletion of majority carriers from silicon SOURCE: Ukrayins'kyy fizychnyy zhurnal, v. 10, no. 4, 1965, 389-397 TOPIC TAGS: field effect, nonequilibrium effect, silicon, carrier depletion, conductivity modulation ABSTRACT; This is a theoretical explanation of the field effect in non-equilibrium depletion, proposed in the preceding paper in the same source (Accession Er. 5011064). The change in the space charge, the electric field, the conductivity, and capacitance of the semiconductor are calculated as functions of the potential drop scross the semiconductor in the non-equilibrium mode. It is shown that the calculated value of the depth of penetration of the field at the instant of the blocking of the current coincides with the thickness of the silicon plate, while the calculated value of the mobility of the field effect, with account of the change in the capacitance coincides in the case of large fields with the drift

Card 1/2

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	그리라 조망과 화장 하겠다면 되었다.	[14] [15] [16] [16] [16] [16] [16] [16] [16] [16	
L 51444-65	등 보이 아름아 불어놓았다면서 얼굴을 다		
ACCESSION NR: AP5011065	민들은 경기가 보다를 맞아도 있는데?		
modility of the holes in t	the volume. This offers eviden	ice of the quantitative	
agreement between the the	oretical model and the experime	ental data, and confirms	
the main idea of the propo	osed mechanism, in which the do	minant role is played by	
the majority carriers and	the change in the conductivity	and in the slowing down	
of the rate of their gener	ration with decreasing temperat	tures from the surface lev-	
er. The generation of the	e majority carriers within the	Volume of the semiconduct-	
or from local centers, and	d the generation of the minorit	y carriers, apparently	
play no essential role. (	orig. art. has: 8 figures and	14 formulas.	
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play no essential role. ( ASSOCIATION: Instytyt name	Orig. art. has: 8 figures and Divprovidnykiv AN URSR. Kyyiv [	14 formulas.  Institut poluprovodnikov	
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EWT(m)/EPF(c)/EWP(t)/EWP(b) JD/WB IJP(c) L 1562-66 UR/0185/65/010/007/0745/0752 ACCESSION NR: AP5018635 Nesterenko, B. O. (Nesterenko, B. A.); Snitko, O. V. AUTHORS: Effect of oxidation on the properties of an atomically clean TITLE: silicon surface SOURCE: Ukrayins kyy fizychnyy zhurnal, v. 10, no. 7, 1965, 745-752 oxidation, surface ionization, surface property, silicon TOPIC TAGS: The purpose of the work was to obtain information on the ABSTRACT: type, concentration, and other parameters of electronic levels of atomically clean and oxidized surfaces of silicon by studying the surface conductivity, the direct-current and voltage-pulse field effects, the noise and rate of recombination. Four samples cut out from single-crystal p-type silicon parallel to (111) were investigated at 295K. The specific resistance of the samples was 600 -- 1000 ohm-cm. The surface was bombarded with argon ions with subsequent heating to 1000K in a vacuum no worse than 1 x  $10^{-9}$  mm Hg. Amplitudes of  $\pm 200$  v Card 1/3

L 1562-66	7
odession NR: AP5018635  Ind 40 usec to 2 millisec long were used in the studies with voltage- ulse field effect. The hole conductivity of an atomically clean  urface was found to be 1.3 x 10 <sup>-7</sup> ohm <sup>-1</sup> . The adsorption of oxygen  t 5 x 10 <sup>-7</sup> mm Hg leads to an increase of the surface conductivity by  x 10 <sup>-8</sup> ohm <sup>-1</sup> . Further oxidation does not lead to appreciable change t is shown that an atomically clean surface of p-type silicon has a  urface potential Y = 712 kT/e. The nonexponential decay of the  induced conductivity in the voltage-pulse field effect indicates  creening of the external field by several different energy levels.  The rate of surface recombination on a clean surface is large (1.2 x  odo cm/sec). The noise obeys a 1/f law. Oxidation of the surface  iffects its properties, with the exception of the kinetics of the  cled effect and noise, little. A correlation is observed in the  change of the kinetics of the field effect and noise on oxidation. I  shange of the kinetics of fast surface states in the noise	ges.
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APPROVED FOR RELEASE: 08/25/2000 CIA-RDP86-00513R001651810015-3"

L 1562-66 ACCESSION NR:	AP5018635			ζ	
dation proces between atomi conclusion th V. I. Lyashen	s is demonstrate cally clean sure authors expreko, senior scie	he appearance of ed. Considerable faces of silicons their sincerentist V. G. Literatusi discussion de la constant de la consta	and germaniue gratitude to ovchenko, and	m. 'In Professor junior sci- sults and	
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L 5266-66 EWT(1)/EWT(m)/T/EWP(t)/EWP(b)/EWA(h) IJP(c) JD/AT SOURCE CODE: UR/O109/65/010/009/1733/1735 ACC NR: AP5022445 AUTHOR: Primachenko, V. Ye.; Snitko, O. V.; Matsas, Ye. P. TITLE: Investigation of the gold-doped physical surface of germanium ORG: none SOURCE: Radiotekhnika i elektronika, v. 10, no. 9, 1965, 1733-1735 TOPIC TAGS: germanium semiconductor, semiconductor research ABSTRACT: The results of an experimental investigation of n-Ge specimens (45 ohms-cm, volume lifetime, 1 msec) etchant-doped with Au are reported. Fast-state charge vs. surface potential and surface recombination rate vs. surface potential curves are shown. It is found that the Au-doping produces a second recombination level located above the  $E_1$  ( $E_2$  = +6kT) with capture cross-sections of  $C_{n2}$  = 10<sup>-16</sup> cm<sup>2</sup>,  $C_{\rm p2} = 3 \times 10^{-13} \ {\rm cm^2}$  (acceptor level). The Au-doping also creates a set of fast nonrecombination states located higher and lower than the center of the forbidden band Ei as compared to Ei and E2. The authors wish to thank N. A. Petrova for her help in doping the specimens." Orig. art. has: 2 figures. UDC: 539.293,011.7:535.215.12:546.289 ORIG REF: 003/ OTH REF: 003 1 SUB CODE: EC/ SUBM DATE: 23Nov64/ 0901

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L 20401-66 EWP(t) IJP(c) JD

ACC NR: AP5024755 SOURCE CODE: GE/0030/65/011/002/0711/0718

AUTHOR: Primachenko, V. E.; Snitko, O. V.; Milenin, V. V.

41

ORG: Institute of Semiconductors, Academy of Sciences UkrSSR, Kiev

TITLE: Nonequilibrium field effect on Si in the region of high depletion

SOURCE: Physica status solidi, v. 11, no. 2, 1965, 711-718

TOPIC TAGS: silicon semiconductor, electric conductivity, semiconductor band structure, nonequilibrium

ABSTRACT: The features of the non-equilibrium field effect are investigated for silicon in the region of high majority carrier depletion and non-equilibrium between the energy bands. The observed effects are a strong asymmetry of the amplitude dependence of conductivity with respect to the sign of the external field, a current-pinch effect, and a strong dependence of the kinetics of field effect

Card 1/2

#### L 20401-66

ACC NR: AP5024755

on field strength, temperature, and light intensity. A mechanism is proposed for the non-equilibrium field effect in the depletion region which involves a strong retardation of screening by surface states at low temperatures and thus allows penetration of the field into the volume of the crystal. The experimental data agree quantitatively with the calculation. Orig. art. has: 4 formulas, 10 figures. [Based on author's abstract]

SUB CODE: 20,09/ SUBM DATE: 16Ju165/ SOV REF: 003/ OTH REF: 003/

Card 2/2 BK

L 23113-66 EWT(m)/EWP(t) IJP(c) JD/JG

ACC NR: AP6006870 SOURCE CODE: UR/0181/66/008/002/0611/0613

AUTHOR: Klimovskaya, A. I.; Snitko, O. V.

ORG: Institute of Semiconductors, AN UkrSSR, Kiev (Institut poluprovodnikov AN

Ukrssr)

TITIE: Influence of the adsorption of gold, aluminum, and antimony on the properties of atomically-pure germanium surface

SOURCE: Fizika tveriogo tela, v. 8, no. 2, 1966, 611-613

TOPIC TAGS: germanium, surface property, adsorption, electric conductivity, field emission, valence band, semiconductor impurity, aluminum, gold, antimony

ABSTRACT: To determine the properties of atomically-pure germanium surfaces and surfaces doped with certain elements, the authors investigated at 23C the surface conductivity of p-germanium with resistivity 40--50 ohm-cm and its response to an external electric field (field effect). The samples (0.5 x 0.5 x 0.05 cm) were cut parallel to the (111) plane and placed in an experimental tube, the pressure in which was maintained at a level down to ~1 x 10<sup>-9</sup> torr. The surface was cleaned by cathode sputtering of the germanium in an argon atmosphere followed by annealing. The conductivity was measured with the aid of sealed-in molybdenum contacts. The field effect at constant voltage was measured with the aid of a field elec-

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L 23113-66

ACC NR: AP6006870

trace mounted over the surface of the sample. An investigation of the dependence of the conductivity on the charge induced on the surface has shown that an atomically-pure germanium surface has a clearly pronounced conductivity of p-type, brought about by a large negative charge (1--7) x 1012 el/cm2 in the surface acceptor states located near the top of the valence band. Deposition of impurities on the atomically-pure surface changed its properties markedly. Gold and aluminum increased the resistivity with increasing concentration, while an increased concentration of antimony decreased surface resistivity. The field effect was also found to be strongly influenced by the state of the surface when gold was used for doping. Antimony exerted no influence on the field effect, although it did change the conductivity to a considerable degree. This indicates that gold forms acceptor surface states near the top of the valence band, screening the external electric field, while antimony produces donor states which lie above the valence band and above the Fermi level, and therefore do not take part in the screening. Both aluminum and antimony form acceptor and donor states on the surface of the germani um, in analogy with their behavior in the interior of the germanium. No such behavior is observed for gold. Orig. art. has: 2 figures and 1 table.

SUB CODE: 20/ SUBM DATE: 20Sep65/ ORIG REF: 002/ OTH REF: 005

Card 2/2

I. 8967-66 EWT(1)/EWT(m)/T/EWP(t)/EWP(b)/EWA(b) LJP(c) JD/AT  ACC NR. AP5027432 SOURCE CODE: UR/0181/65/007/011/3422/3424
ACC NR. AP5027432 SOURCE CODE: UR/0181/65/007/011/3422/3424
AUTHOR: Pasechnik, Yu. A.; Snitko, O. V.
1111 1 Company of the
ORG: Institute of Semiconductors AN UkrSSR, Kiev (Institute popuprovodnikov AN UkrSSR)
TITLE: Infrared photoconductivity of silicon due to electron surface states
SOURCE: Fizika twerdogo tela, v. 7, no. 11, 1965, 3422-3424
TOPIC TAGS: photoconductivity, IR photoconductor, silicon semiconductor
TOPIC TAGS: photoconductivity, IR photoconductor, silicon semiconductor
ABSTRACT: Experiments are conducted to detect impurity surface photoconductivity in
gold-doned polished silicon. The specimens were p-type silicon with a resistivity or
3500 Ω·cm and a carrier lifetime of 700 µsec, with dimensions of 1.2 × 0.4 × 0.05 cm.  IR photoconductivity spectra are given for specimens before and after polishing, and
before and after doning. Photoconductivity begins at 4.07 µ for a polished surface,
and at 3.78 u for a gold-doped surface and then increases monotonically as the wave-
length is reduced. Studies of the effect of an external electric field on the impuri-
ty photoconductivity in these specimens showed an increase in the effect when a positive surface charge is induced. A theoretical explanation is given for the phenomena
observed. The authors are grateful to V. Ye. Primachenko, V. G. Litovchenko and U. S.
Frolov for discussion of the work. Orig. art. has: \2 figures.
SUB CODE: 20/ SUBM DATE: 31May65/ ORIG REF: 004/ OTH REF: 003
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SOURCE CODE: UR/0185/66/011/012/1316/1323

AUTHOR: Snitko, O. V.; Pasichnyk, Yu. A. Pasechnik, Yu. A.

ORG: Institute of Semiconductors, AN URSR, (Instytut napivpro yidnykiv AN URSR)

TITLE: Investigation of extrinsic photoconductivity of a gold-doped silicon surface

SOURCE: Ukrayinsk'kyy fizychnyy zhurnal, v. 11, no. 12, 1966, 1316-1323

TOPIC TAGS: photoconductivity, IR photoelectric cell, 1R photoconductor, 1R spectrum

ABSTRACT: The extrinsic infrared photoconductivity spectrum of a silicon surface dope doped with gold was studied. Specimens of p-type (800—3500 ohm.cm resistivity) and n-type (resistivity 300 ohm.cm) silicon measuring 1 x 0.5 x 0.05 cm were used. Surface infrared conductivity was observed as temperature decreased. The magnitude and shape of the spectrum were dependent on the gold concentration in the etchant. The external electrical field affected surface intrinsic photoconductivity; the greatest effect was observed for the long-wave region of the spectrum. This proposed mechanism of surface infrared photoconductivity is in good qualitative agreement with experimental results. Orig. art. has: 5 figures and 6 formulas. [WP]

SUB CODE: 20/ SUBM DATE: 13Apr66/ ORIG REF: 007/ OTH REF: 003

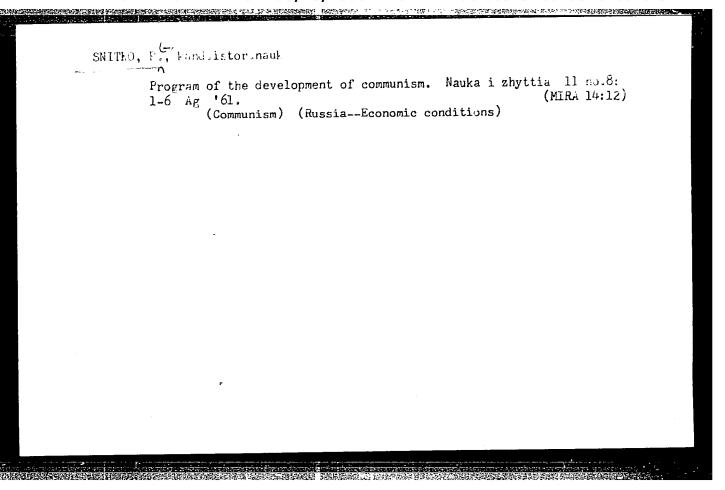
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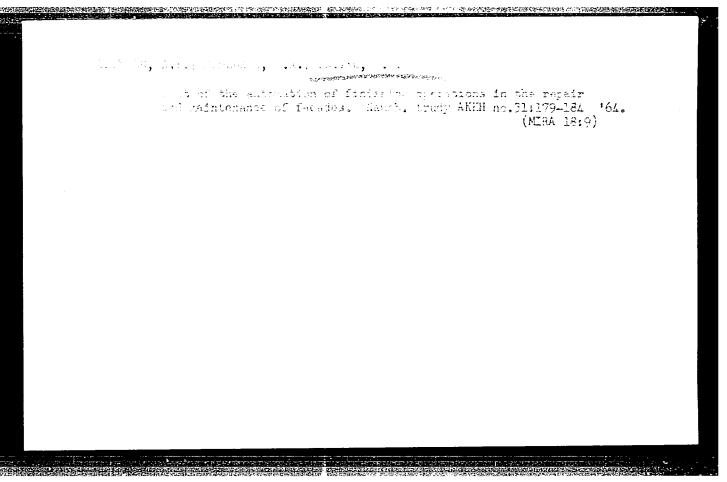
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SEDLUKHA, G.A., inzh.; SNITKO, V.A., inzh.; UKUNICH, A.B., anni. tekhn. nauk

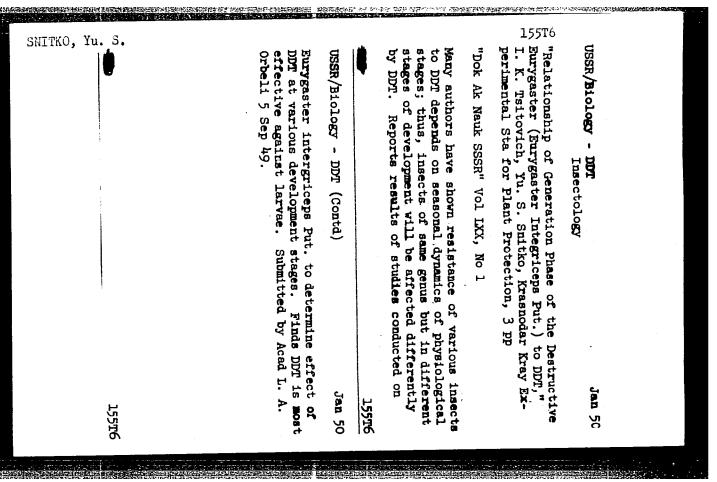
Automating finishing operations on facades of buildings. Etroi.
i dor. mash. 9 no.3:15-17 Mr '64.

(MIRA 17:6)

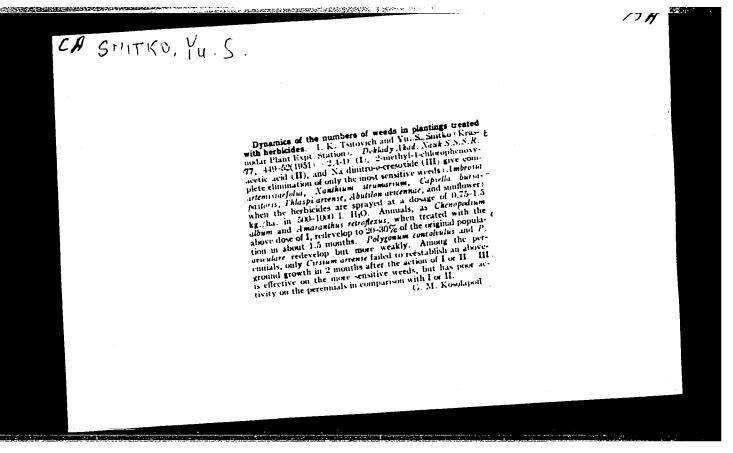


SHITKO, Vladimir Aleksandrovich; SEDLUKHA, Georgiy Andrianovich; LEVCHENKO, Ya.V., red.

[New machines for facade operations] Novye mashiny dlia fasadnykh rabet. Leningrad, 1965. 22 p. (MIRA 18:7)



Data on Comparative Tests.for the Evaluation of Damestic Herbicides, "I. K. Tsitolich, fir. S. Shitke, Krasnodar Expt Station of Plant Protection  Agrobiologiya" No 6, pp 129-132  Agrobiologiya Nests on the entermine- tion of weeds in wheat fields with 2,4-DU [5,4-dichlorophenoxyscetic soid/, 2M-4M [2-dethyl-4-chlorophenoxyscetic soid/, 2M-4M [2-dichlorophenoxyscetic soid/, and [2-dethyl-4-chlorophenoxyscetic soid/, and [2-dethyl-4-chlorophenoxysce
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ACC NR: AP7006118

SOURCE CODE: UR/0209/67/000/001/0060/0063

AUTHORS: Snitkovskiy, A. (Candidate of geographical sciences); Sorochinskiy, M. (Candidate of geographical sciences); Pshenichner, B.

ORG: none

TITLE: The satellite searches for hurricanes

SOURCE: Aviatsiya i kosmonavtika, no. 1, 1967, 60-63

TOPIC TAGS: meteorologic satellite, weather forecasting, storm, heat radiation, meteorologic research facility

ABSTRACT: Meteorologic satellites are put into orbits of 600--800 km to relay information and advance warning on the formation and location of hurricanes and cyclones. The satellites also relay information on the distribution of solar energy for long-range weather forecasting and on the distribution of the ultraviolet sector of the solar spectrum for determining ozone content and for studying the optic properties of the atmosphere. Kosmos-122 measures atmospheric radiation, radiation, from the earth, elements of radiation balance, and radiation in ranges microns and 8--12 microns. Cameras on board take infrared pictures on day and night sides of the earth. Computers reduce the data for a global chart showing distribution of radiation intensity. Plans call for launching additional weather satellites which

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ACC NR: AT6032990 SOURCE CODE: UR/2546/66/000/149/0097/0101

AUTHOR: Snitkovskiy, A. I.

ORG: Central Institute of Forecasts (Tsentral'nyy institut prognozov)

TILLE: Kinetic energy distribution in an intensively deepening cyclone

SOURCE: Moscow. Tsentral'nyy institut prognozov. Trudy, no. 149, 1966. Rezul'taty ispytaniy razlichnykh sposobov kratkosrochnykh prognozov pogody (Results of analyses of various short-range weather forecasting methods), 97-101

TOPIC TAGS: atmospheric physics, cyclone energy, cyclogenesis, atmospheric kinetic energy, high wind , CYCLONE, WIND YELOCITY

ABSTRACT: At 0300 hr on 29 September 1963, a poorly defined wave disturbance appeared on an Arctic front over the southwestern part of the Black Sea. A slight drop in pressure preceded the warm front. On 29 September, the pressure dropped 2.3 mb in 3 hr, and a 1013-mb cyclone appeared at the peak of the wave disturbance. The pressure in the cyclone dropped to 951 mb by 1500 hr on 1 October, then the pressure at the center of the cyclone began to rise. While deepening, the cyclone travelled 2600 km from the Black Sea to Syktyvkar. Ground-level wind speeds behind the cold front reached 25-40 m/sec (55-88 mph).

Card 1/3

•	and contributes to the increase in the kinetic energy at ground level; this leads, in time, to rising winds at ground level, even at the beginning of the cyclone. [WA-50; CBE No. 12]						
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A study was made of the kinetic energy in different parts of the cyclone and its changes in time, from the appearance of the wave until the cyclone had filled at ground level, with measurements made at ground level and on the 850-, 700-, 500-, 300-, and 200-mb surfaces at 0300 and 1500 hrs Moscow time. These values were calculated in knots per unit mass, then averaged for areas of 1500 x 1500 and 500 x 500 km<sup>2</sup>. The network was a grid of 1500 km on each side (7  $\times$  7 points per step of 250 km, subdivided into 9 smaller squares of 500 x 500  $km^2$ ). The wind speeds on the 850-, 700-, 500-, 300-, and 200-mb surfaces are assumed to be equal to geostrophic wind speeds. The center of each square was superposed on the crest of the wave or the center of the cyclone at the surface when obtaining data on pressures and the geopotential needed to calculate wind speeds on the isobaric surfaces. Wind speeds were calculated by finite-difference formulas, and all calculations of the kinetic energy were run on a high-speed computer. Analysis of the data showed that most of the change in kinetic energy in the middle and upper troposphere occurred in the first few 12-hr periods after the cyclone appeared at ground level; this makes it reasonable to assume that during cyclogenesis, part of the energy at high levels is transferred to lower levels

Card 2/3

L 62972-65 EWT(1)/FCC GW ACCESSION NR: AT5016799

UR/2546/65/000/146/0053/0062

AUTHOR: Snitkovskiy, A. I.

TITLE: The distribution of energy along a vertical and its relation to the evolution and movement of cyclones

SOURCE: Moscow. Tsentral'nyy institut prognozov. Trudy, no. 146, 1965. Regional nyye zakonomernosti i prognoz gidrometeorologicheskikh yavleniy (Regional regularities and forecasting of hydrometeorological phenomena), 53-62

TOPIC TAGS: cyclone, climatology, meteorology, weather forecasting, atmosphere, atmospheric movement

ABSTRACT: The distribution and time variation of kinetic, potential, and internal energy in cyclones are studied. For this purpose a column of the atmosphere from the surface of the earth to the 200-millibar surface was selected. Energy calculations were conducted for basic aerological periods of observation (0300 and 1500 hours, Moscow time). Observations began with the moment of cyclone apparition at the earth's surface and terminated either with the cyclone's disappearance or after the cyclone had reached a developed condition. In all, ten cyclones were observed during 1962 and 1963 in the European territory of the SSSR. In each instance the kinetic energy was computed over an area 1500-km square, with the center of the Cord 1/2

L 62972-65
ACCESSION NR: AT5016799
cyclone corresponding to the center of observation. Working formulae were: 1)
energy relative to unit mass $K_{es} = \frac{\sigma^2}{2}$ , where v is the wind speed at selected
millibar levels, given in meters/second by $v = 1,146 \frac{1}{0n}$ where $\frac{1}{0n}$ .
gradient in millibars at 500 km, 2) mean layer temperature $T = \frac{H_p - H_{p_0}}{67,4424 \lg \frac{p_0}{p}}$
Thorag H and H are the geopotentials of isobar surfaces p and po, and 3) potential
energy $II = p_1 z_1 - p_2 z_2 + (x - 1)/$ , where $x = \frac{c_p}{c_p}$ : the ratio of heat capacitance at constant pressure to heat capacitance at constant volume. A plot is made of the
delinette congression on chaptred cyclone. Test data revealed did inverted
energy decreases rapidly with increased height above the earth. Potential energy increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during cyclone development at low levels and generally decreases at higher increases during the cyclone development at low levels and generally decreases at higher the cyclone development at low levels and generally decreases at higher the cyclone development at low levels and general decreases at higher the cyclone development at low levels and general decreases at higher the cyclone development at low levels and general decreases at higher the cyclone development at low levels and general decreases at higher the cyclone development at low levels and general decreases at higher the cyclone development at low levels and general decreases at levels and general decreases a
levels. Several equations describing the redistribution and movement of cyclone energy are developed. Orig. art. has: 1 figure, 20 equations, and 4 tables.
ASSOCIATION: Tsentral'nyy institut prognozov (Central Forecasting Institute)
STR CODE: ES
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ACC NR: AT6032990

SOURCE CODE: UR/2546/66/000/149/0097/0101

AUTHOR: Snitkovskiy, A. I.

ORG: Central Institute of Forecasts (Tsentral'nyy institut prognozov)

TILLE: Kinetic energy distribution in an intensively deepening cyclone

SOURCE: Moscow. Tsentral'nyy institut prognozov. Trudy, no. 149, 1966. Rezul'taty ispytaniy razlichnykh sposobov kratkosrochnykh prognozov pogody (Results of analyses of various short-range weather forecasting methods). 97-101

TOPIC TAGS: atmospheric physics, cyclone energy, cyclogenesis, atmospheric kinetic energy, high wind , CYCLONE, WIND YELOCITY

ABSTRACT: At 0300 hr on 29 September 1963, a poorly defined wave disturbance appeared on an Arctic front over the southwestern part of the Black Sea. A slight drop in pressure preceded the warm front. On 29 September, the pressure dropped 2.3 mb in 3 hr, and a 1013-mb cyclone appeared at the peak of the wave disturbance. The pressure in the cyclone dropped to 951 mb by 1500 hr on 1 October, then the pressure at the center of the cyclone began to rise. While deepening, the cyclone travelled 2600 km from the Black Sea to Syktyvkar. Ground-level wind speeds behind the cold front reached 25-40 m/sec (55-88 mph).

Card 1/3

ACC NR: AT6032990

A study was made of the kinetic energy in different parts of the cyclone and its changes in time, from the appearance of the wave until the cyclone had filled at ground level, with measurements made at ground level and on the 850-, 700-, 500-, 300-, and 200-mb surfaces at 0300 and 1500 hrs Moscow time. These values were calculated in knots per unit mass, then averaged for areas of 1500 x 1500 and 500 x 500 km<sup>2</sup>. The network was a grid of 1500 km on each side (7 x 7 points per step of 250 km, subdivided into 9 smaller squares of 500 x 500 km<sup>2</sup>). The wind speeds on the 850-, 700-, 500-, 300-, and 200-mb surfaces are assumed to be equal to geostrophic wind speeds. The center of each square was superposed on the crest of the wave or the center of the cyclone at the surface when obtaining data on pressures and the geopotential needed to calculate wind speeds on the isobaric surfaces. Wind speeds were calculated by finite-difference formulas, and all calculations of the kinetic energy were run on a high-speed computer. Analysis of the data showed that most of the change in kinetic energy in the middle and upper troposphere occurred in the first few 12-hr periods after the cyclone appeared at ground level; this makes it reasonable to assume that during cyclogenesis, part of the energy at high levels is transferred to lower levels

Card 2/3

	level	and contributes to the increase in the kinetic energy at ground level; this leads, in time, to rising winds at ground level, even at the beginning of the cyclone. [WA-50; CBE No. 12]						<b>.</b> !
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ACC NR: AT7006723

SOURCE CODE: UR/2546/66/000/158/0003/0010

AUTHOR: Snitkovskiy, A. I.

ORG: none

TITLE: Energy distribution in the region of a cyclone at various stages of its development

SOURCE: Moscow. Tsentral'nyy institut prognozov. Trudy. no. 158, 1966. Sinopticheskaya meteorologiya (Synoptic meteorology), 3-10

TOPIC TAGS: kinetic energy, internal energy, wind, cyclone, ATMOSPHERIC GEOPERATURE, GEOSTROPHIC WIND

ABSTRACT: The author has examined the distribution and change with time of the kinetic, potential, and internal energy in cyclones, from the earth's surface to the 200-millibar level. Ten cyclones of 1962 and 1963 in European SESR were selected for computations. Energies were computed for points at intersections 250 km apart on a square grid 1500 km on a side. The geostrophic wind was used for computing kinetic energy. The internal and potential energies were computed for a vertical column of air of unit cross section, and were computed separately for layers limited by the principal isobaric surfaces (200 and 300, 300 and 500, 500 and 700, 700 and 850 millibars), and also for the total column from the earth to the 850-millibar level. Exps were then plotted to show energy distribution at four different stages of cyclonic development. The shifting of energy highs may be seen on these maps. It

Card 1/2

ACC NR: . AT7006723

was found that as a cyclone develops at the earth's surface to the maximal stage, an essential factor in increasing the kinetic energy in the lower layer of the atmosphere is transfer of energy from the upper layers, chiefly through internal friction. The various changes in energies for the different stages of cyclonic development and for different levels are discussed and compared with values when no cyclone is developing. Orig. art. has: 3 figures and 3 tables.

SUB CODE: 04/ SUBM DATE: none/ ORIG REF: 002

Card 2/2

ACC NR: AT7006732

SOURCE CODE: UR/2546/66/000/158/0085/0089

AUTHOR: Snitkovskiy, A. I.

ORG: none

TITLE: The relation of kinetic energy to precipitation

SOURCE: Moscow. Tsentral'nyy institut prognozov. Trudy, no. 158, 1966. Sinopticheskaya meteorologiya (Synoptic meteorology), 85-89

TOPIC TAGS: weather forecasting, kinetic energy, atmospheric pressure, atmospheric precipitation

ABSTRACT: This paper examines the relation of the kinetic energy at different pressure surfaces to the amount of precipitation at the earth's surface. Twenty-eight cyclones of the cold months (November to February) observed in European SSSR during 1962--63 were selected for study. Choice of the cold months eliminated to a great extent the effect of convection on the amount of precipitation. Kinetic energy was computed, according to a method previously proposed by the author, for the 050-, 700-, 500-, 300-, and 200-millibar surfaces in different parts of the cyclone. Precipitation data were taken for each day at the hours of 7 a.m. and 7 p.m. local time. The coefficient of correlation and the correlation ratio were then calculated for the various levels, averaged over areas of different size (500 x 500 km and 1500 x 1500 km). Correlation improved appreciably with increase in size of area being Cord 1/2

ACC NR: AT7006732

averaged. Comparison of the Laplacian of the pressure with amount of precipitation indicated acceptable correlation. It was found that the values of kinetic energy at the different levels have a linear relationship. This is indicated by the high value of the correlation coefficient and by the fact that the correlation ratio differs but little from the correlation coefficient. The author suggests that good correlation between kinetic energy and precipitation and between values of kinetic energy at different pressure levels may be obtained by using sufficiently large areas for averaging and large time intervals. Orig. art. has: 1 figure and 2 tables.

SUB CODE: 04/

SUBM DATE: none/

ORIG REF: OO1/

OTH REF: 002

Card 2/2

SOV/137-59-3-5795

Translation from: Referativnyy zhurnal. Metallurgiya, 1959, Nr 3, p 121 (USSR)

Snitkovskiy, M. M. AUTHOR:

On the Strength of Cast-iron Welds and on Methods of Their Testing (K voprosu o prochnosti i metodike ispytaniy svarnykh soyedineniy TITLE:

chuguna)

PERIODICAL: Nauchn. tr. Odessk. in-ta inzh. morsk. flota, 1958, Nr 17, pp

50-55

ABSTRACT: Strong cast-iron welds may be achieved only if a proper combination of several factors is observed; in addition to metallurgical and

metallographic considerations, these factors should also include considerations on the operating conditions of the metal deposited. A method is described whereby the strength of a cast-iron weld operating under complex stress conditions may be evaluated with an accuracy sufficient for all practical purposes by means of testing of special specimens consisting of a metal strip with a milled slot in

the center having a V-shaped cross section and a length of 35-40 mm. Preparatory to testing, holes 6 mm in diameter are drilled along the

edges of the slot. A strip intended for testing on a 30-ton Card 1/2

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On the Strength of Cast-iron Welds and on Methods of Their Testing \$SOV/137-59-3-5795\$

tension-testing machine is 300 mm long, 85 mm wide, and 17 mm thick. The slot, which simulates a crack, is welded under conditions identical to those which would be encountered in repairing an actual working part. The strength of a weld thus tested may be evaluated by determining a nominal value of  $\sigma_b$  therefor; the quality of a cast-iron weld is considered satisfactory if its nominal  $\sigma_b$  value is equal to 80% of the  $\sigma_b$  of the material of the strip.

Card 2/2

Repair of "Gants-Endrashik" 216-310 engine crankcase and of 6DR 30/50 engine blocks by means of a tightening device. Mor. flot 18 no.2:21 F '58. (MIRA 11:2)

1. Odesskiy institut inzhenerov morskogo flota.

(Marine engines--Maintenance and repair)

SNITKOVSKTY, M. M., Cand Tech Sci (diss) -- "Investigation of a tie-tar method, and experience in using it in the repair of cast-iron parts". Odessa, 1960.

14 pp (Min Higher and Inter Spec Educ Ukr SSR, Odessa Polytech Inst), 250 copies (KL, No 14, 1960, 133)

SNITKOVSKIY, M.M., inzh.; SILAYEV, I.I., inzh. Changes in the microhardness of phosphorus compound inclusions in gray cast iron at from 20 to 3000 temperatures. Metalloved. i term. obr. met. no. 5:42-45 My 160.

> 1. Odesskiy institut inzhenerov morskogo flota. (Cast iron--Metallography) (Metals at high temperatures)

(MIRA 13:12)

SNITKOVSKIY, M.M., inzh.

Effect of hardening on the wear resistance of gray pearlitic cast iron. Metalloved. i term. obr. met. no.5:32-34 My '61.

(Cast iron--Hardening)

(Cast iron--Hardening)

STAROSEL'SKIY, A.A., dotsent; SNITKOVSKIY, M.M., assistent; PASHKOV, A.P., assistent.

Wear resistance of some gray pearlitic cast irons in connection with joining them in friction pairs. Izv.vys.ucheb.zav.; mashinostr. no.7:95-100 '61. (MIRA 14:9)

SMITKOVSKIY M.M. assistent, SILAYWV, I.I., inzh.

Mechanism of the wear of gray phosphorous cast iron caused by

friction. Izv.vys.ucheb.zav.; masninostr. no.10:37-36 161. (NIFA 14:12)

IVANOV, S.A., dotsent; SILAYEV, I.I., inzh.; SMITKCVSKIY, M.M., inzh.

Gauses of seam failure in expanding welded boiler tubes. Stal!
22 no.1:72-73 Ja '62. (MIRA 14:12)

1. Odesskiy institut inzhenerov morskogo flota. (Boilers, Water tube--Welding)

AUTHORS: Snitkovskiy, M. M.; Yegorov, N. V.; Golomazyuk, V.

TITLE: Increase in strength of R18 steel by swaging

SOURCE: Metallovedeniye i termicheskaya obrabotka metallov, no. 9, 1963, 19-22

TOPIC TAGS: swaging, cutting tool, R18 steel, austenite grain, carbide eutectic, metal stamping, austenization

ABSTRACT: Authors examined the effect of swaging upon the stability of cutting tools made out of R18 steel. The tools were swaged in a stamp with a conical die. After swaging, they were face-ground to a depth of 1-2 mm in order to remove the surface crust. Temperature and heating time varied. The effect of austenite grain growth and carbide eutectic upon the stability of the swaged cutting tools were examined.

Card 1/2

L 18918-63

ACCESSION NR: AP3006603

Authors found that swaging at a pressure of about 7000 kg/cm<sup>8</sup> increases the stability of cutting tools made out of R18 steel by 40-50%. Grain growth does not reduce the observed effect. Combining of the stamping and heat treatment operations greatly simplifies the technology of cutting tool production. This has a great practical significance in the mass production of cutting tools with complex shapes (milling cutters, drills, cutting tools, etc). The wear resistance during swaging is augmented on account of an increase in the dispersion of the submicrostructure. In contrast to austenitization, swaging brings about a volumetric change of the R18 steel's properties. Orig. art. has: 5 figures and 1 table.

ASSOCIATION: Odesskiy institut inzhenerov morskogo flota (Odessa institute of merchant marine engineers)

SUBMITTED: 00 DATE ACQ: 030ct63 ENCL: 00

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5/0126/64/017/003/0400/0407

ACCESSION NR: AP4028998

AUTHORS: Perkas, M. D.; Snitsar', V. I.

TITLE: The influence of alloying elements on martensite hardness in heated iron-nickel alloys

SOURCE: Fizika metallov i metallovedeniye, v. 17, no. 3, 1964, 400-407

TOPIC TAGS: iron-nickel alloy, martensite, alloying element, Ti, Al, Mn, Nb, Zr, Mo, martensite hardness, martensite aging, metal structure, Vickers hardness, phase composition, elasticity modulus

ABSTRACT: The influence on martensite aging of Ti, Al, Mn, No, Zr, and Mo additions to iron-nickel alloys was investigated. Experimental 5-kg ingots containing 1.0-2.0 wt % of alloying elements were cast and forged into rods 20 x 10 mm and into disks 11 mm in diameter. Martensitic structure was produced by air cooling of specimens. Their hardness (Vickers) and modulus of elasticity were determined after tempering and aging at various temperatures. The effect of adding alloying elements to material with 16.5-18.0% Ni shown in Fig. 1 of the Enclosures. The same effect produced on material with 8.0%

Card 1/82

- ACCESSION NR: AP4028998

Ni by addition of Ti and Al (separately and jointly) may be seen in Fig. 2. It was determined that martensite hardening increases with the increase of nickel content and disappears below 2.0% Ni. Joint addition of several elements serves to strengthen the ~-phase. The process of hardening ceases at about 500C and is reversed at higher temperatures. The variation of the ~-phase strength was found to be related to the number of defects in the original structure, and increased with the number of defects. The modulus of elasticity was determined by measuring the changes in the resonance frequencies of longitudinal oscillations. The changes in the modulus became apparent at 350C, with the maximum being reached at 500C (see Fig. 3 of the Enclosures). For comparison, Fig. 3 also shows the change of hardness with temperature. Orig. art. has: 9 graphs.

ASSOCIATION: Institut metallovedeniya i fiziki metallov TsNIIChM (Institute of Metallurgy and Physics of Metals, TsNIIChM)

SUBMITTED: 13May63

DATE AQ: 27Apr6l;

ENCL: 03

SUB CODE: ML, PH

NO REF SOV: 003

OTHER: 004

Card 2/\$2

Planning and building compartment dams on bedrock foundations.  Gidr.stroi 23 no.7:41-42 '54. (MLRA 7:11)					
(Dams)	7.41042 )4.		(		

SNITSAR, Ya.Ye. inzhener.

Construction of a pressure tunnel of a small hydroelectric power plant on the Smotrich River. Gidr. strei.25 no.5:48-49 Je '56.

(Smotrich River--Hydroelectric power stations) (MLRA 9:9)

SKITSAK, YASTE

AUTHOR:

Snitsar, Ya.Ye., Engineer

98-7-9/20

TITLE:

The Siphon Lock on a Spillway Dam (Sifonnyy zatvor vodosliv-

noy plotiny)

PERIODICAL:

Gidrotekhnicheskoye Stroitel'stvo, 1957, No 7, pp 35-37 (USSR)

ABSTRACT:

The proposed lock has 2 working positions one for periods of low water with a curved hinged lock and a siphon for periods of high water. The curved surface of the lock forms a siphon, which divides the flow going over the dam into 2 parts: the lower stream, which flows through the siphon, and the upper streams, which flows over the conventional spillway. The separation of the stream utilizes the ejection force of the upper stream acting upon the discharge capacity of the siphon, and enabling the disposal of floating obstacles, past the siphon into the tail race. The hinge of the locking device is located on a line with the equivalent force of horizontal water pressure, and corresponds to the center of gravity of the lock. Further rising of the water level brings the lock into the second working position, and water starts to flow over the dam, creating a vacuum in 2 places. The most effective vacuum action occurs at the head or at the beginning of the straight part of the lower section.

Card 1/2

The Siphon Lock on a Spillway Dam

98-7-9/20

For this reason the length of the straight part of the lock may equal the height of the siphon pipe. Completed hydraulic computations show that the use of siphon locks increases the discharge capacity of spillways by 20%. This increase may be higher at dams with permanent water pressures.

There are 4 figures.

AVAILABLE:

Library of Congress

Card 2/2

SNITSAR, Ya.Ye. [Snitsar, IA.IE.]

Hydrodynamics method for designing a flat blanket and toe with drains. Dop. AN URSR no.6:620-625 '58. (MIRA 11:9)

1.Giprosel'elektro. Predstavil akademik AN USSR G.N. Savin [H.M. Savin]. (Dams)

UTROBIN, Yevgeniy Nikolayevich; SAVVATEYEV, V.A., kand. ekon. nauk, dots., red.; SNITSARENKO, A.A., red.

[Benefits of the mechanization and automation of production] Chto daet mekhanizatsiia i avtomatizatsiia proizvodstva. Novosibirsk, Novosibirskoe knizhnoe izd-vo. 1961. 35 p. (MIRA 18:7)

ZANIN, Vadim Ivanovich; ISAYEV, Ye.N., kand. ekon. nauk, otv. red.;

SNITSARENKO, A.A., red.; YELISTRATOVA, Ye.M., tekhn. red.

[Working time and labor productivity] Rabochee vremia i
proizvoditel'nost' truda. Novosibirsk, Izd-vo Sibirskogo
otd-nia AN SSSR, 1963. 114 p. (MIRA 16:10)

(Labor productivity) (Time study)

SCMINSKIY, V.S., doktor ekon. nauk, prof., red.; PATRUSHEV, V.D., otv. red.; BLLOUSOVA, V.S., red.; POTEMKIN, P.I., red.; SNITSARENKO, A.A., red.; CVCHINNIKOVA, T.K., tekhn. red.

[Economic problems of mastering new enterprises] Ekonomicheskie voprosy osvoeniia novykh predpriiatii. Pod obshchei red. V.S.Sominskogo. Novosibirsk, Izd-vo Sibirskogo otdniia, 1963. 231 p. (MIRA 16:11)

l. Akademiya nauk SSSR. Sibirskeye otdeleniye. Institut ekonomiki i organizatsii promyshlennogo proizvodstva. (Industrial management)

KOMOVILA, Zinaida Pavlovna; ICOLMIKOV, Grigoriy L'vovich; POTEMKIN, P.I., kand. ekon. nauk, otv. red.; SHITSAKEHKO, A.A., red.

[Overall improvement in planning in industry] Kompleksnoe sovershenstvovanie planirovaniia v promyshlenmosti, Novosibirsk, Red.-izdatel'skii otdel Sibirskogo otd-niia AN SSSR, 1964. 44 p. (MIRA 17:9)

MINIME V, Valentin Amereyevich; ABRAM VICH, P.I., doktor geogr.

nauk, otv. red.; :NiTSARERAD, A.A., red.

[Kamen' Hydroelectric Fower Station on the Ob! River and
the irrigation of the Kulunda Steppe] Kamenskaia GES na
Obi i oroshenie Kulundy. Novosibirsk, Red.-izd. otdel
Sibirskogo otd-niia AN SSSR, 1964. 58 p. (MIRA 17:8)

FOTEMKIN, Four Ivanovich; SOMINSKIY, V.S., prof., ctv. red.; SHITSARENKO, A.A., red.

أرباء المائحة فتتأم المعهاب

[Essays on the methods of evaluating the projected efficiency of new enterprises] Ocherki o metodakh otsenki proektnoi effektivnosti novykh predpriiatii. Novosibirsk, Red.izd. otdel Sibirskogo otd-niia AN SSSR, 1964. 68 p.

(MIRA 17:12)

ZUDINA, Lyudmila Nikolayevna; ISAYEV, Ye.N., kand.ekon.nauk, otv.red.; SNITSARENKO, A.A., red.

[Organization of work in Kuznetsk Basin coal mines] Organizatsiia truda na ugol'nykh shakhtakh Kuzbassa. Novosibirsk, Red.-izd. otdel Sibirskogo otd-niia AN SSSR, 1964. 73 p. (MIRA 17:12)

Machovek My, Alekser Stepanovich; Dekichel M., J.A., and J. I...

nauk, otv. red.; SETTSARENKO, A.A., red.

[The working class of Western Siberia curing the years of the first five-year plan] Raoschil alass Zapadol Sibiri v gody pervol ciatiletki. Novosibirak, Red.-izd. otial Sibirskogo otd-niia AN SSR, 1964. Ho p. (MIRA 18:1)

ARKHIPOV, Stanislav Anatol'yevich; MATVEYEVA, Ol'ga Vladimirovna; PUMINOV, A.P., kand. geol.-mineralog. nauk, otv. red.; SNITSARENKO, A.A., red.

[Cuaternary of the southern margin of the Yenisey Depression.] Antropogen iuzhnoi okrainy Eniseiskoi depresii. Novosibirsk, 1964. 127 p. (Akademiia nauk SSSR. Sibirskoe otdelenie. Institut geologii i geofiziki. Trudy, no.29)

(MIRA 17:12)

l. Institut geologii i geofiziki Sibirskogo otdeleniya AN SSSR (for Puminov).

GOSTREM, Runar Viktorovich; ZINOV'YEV, Gennadiy Stepanovich; STITSARENKO, A.A., red.

[Tunnel diodes and their applications] Tunnel rye diody i ikh primenenie. Novosibirsk, Red.-izd. otdel Sibirskogo otd-niis AN SSSR, 1964. 130 p. (MIRA 18:1)

SWEEL, h.M., st. marchm. both., kard. tekhn. mank, btv. red.; difficultiff, A.A., red.

[hadio communication systems and high-frequency remote control in the mining industry? Hadiosviaz! i vysoko-chestotnala telebahhanika v gornoi procyshlennolti. Gtv. red. h.H.davkin. Hovesibirsk, Had. inc. otdel disirskoro otd-mlia M. 1988, 1964. 173 p. (MIKA 17:8)

1. Akademiya nouk SSEM. Abir: koye otdeleniye. Institut gornopo sels.

MATVEYEVA, F.A., kand. tekhn. nauk, otv. red.; MELEKHOVA, T.F., nauchn. sotr., zam. otv. red.; KVYATKOVSKAYA, K.K., kand. tekhn. nauk, red.; KOSHLYAK, L.L., kand. tekhn. nauk, red.; PLEKHANOVA, Ye.A., nauchn. sotr., red.; SNITSA.EHKO, A.A., red.

STREET, STREET,

[Prospects of the development of the ceramic industries of Siberia and of the Far East; materials] Perspektivy razvitiia keramicheskoi promyshlennosti Sibiri i Dal'nego Vostoka; materialy. Novosibirsk, Red.-izd. otdel Sibirskogo otd-niin AN SSSR, 1964. 183 p. (MIRA 17:11)

l. Soveshchaniye po khimii i tekhnologii keramiki i perspektivam razvitiya keramicheskoy promyshlennosti Sibiri i Dal'nego Vostoka. Novosibirsk, 1962. 2. Khimikometallurgicheskiy institut Sibirskogo otdeleniya AN SSSR (for Matveyeva). 3. Gosudarstvennyy nauchnomissledovatel'skiy institut stroitel'noy keramiki (for Kvyatkovskaya, Koshlyak).

SOBOLEVA, Ariadna Dmitriyevna; TSELLARIUS, Yu.G., kand. med. nauk, otv. red.; SNITSARENKO, A.A., red.

[Fathological anatomy of the lungs in leukemia] Patologicheskaia anatomiia legkikh pri leikoza. Novosibirsk, Red. izd. otdel Sibirskogo otd-niia AN SSSR, 1964. 229 p. (MIRA 17:8)

See a service and a second sec

MEN'SHIKOVA, Z.I.; SHITSARENKO, A.A., red.

[Technical and economic indices in the potash industry and prospects for the expansion of production and consumption of potash fertilizers during the period ending in 1970] Tekhniko-ekonomicheskie pokazateli v kaliinoi promyshlennosti i perspektivy rosta proizvodstva i potreblenija kaliinykh udobrenii na period do 1970 goda. Novosibirsk, Red.-izd. otdel Sibirskogo otd-niia AN SSSR, 1965. 8 p. (MIRA 18:5)

MITSARENKO, A.A., red.

[hethods of controlling ice at hydroelectric power stations in Giberia] Metody bor'by s ledovymi zatrudnenijami na gidrostantsijakh Sibiri. Novosibirsk, Red.-izd. otdel Sibirskogo otd-nija AN SSSR, 1965. 95 p.

(MIRA 18:5)

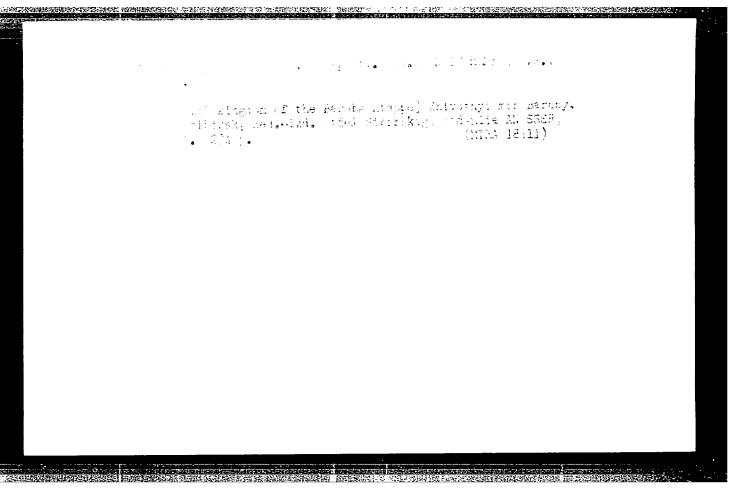
1. Akademiya nauk SSSR, Sibirskoye otdeleniye. Sibirskiy nauchno-issledovatel'skiy institut energetiki.

FETROV, D.F., doktor biol. nauk, otv. red.; SHITSARENKO, A.A., red.

[Breeding of microbes] Selektsiia mikrobov. Novosibirsk, Redaktsionno-izdatel'skii otdel SO AN SSSR, 1965. 132 p.

(MIGA 16:9)

1. Akademiya nauk SSSR. Sibirskoye otdeleniye. Laboratoriya tsitologii rasteniy i apomiksisa.



ZYBIN, Yu.P.; AKULOVA, T.Ye.; SNITSARENKO, L.G.; UL'YANITSKIY, V.A.

Mercury resistance transmitter for measuring large deformations in materials. Trudy Inst. mash. Sem. po teor. mash. 19 no.76:26-33 (MIRA 13:3)

(Strain gauges)

EWT(m)/EWP(j)/T L 3381-66 UR/0138/65/000/008/0042/0044 ACCESSION NR: AP5022093 44678. 06:685. 314. 33. 002. 2 AUTHOR: Tokareva, T. Ye.; Snitsarenko, L. G.; Volkova, N. A. Baksht, O. Zel'dich, E. I., Kheyfets, F. M. uk TITLE: Compounding and technology for manufacturing winter-proof boots SOURCE: Kauchuk i rezina, no. 8, 1965, 42-44 TOPIC TAGS: rubber chemical, antifreeze, synthetic material, butadiene styrene rubber, filler, plasticizer, thermoelasticity, special purpose clothing, rubber/SKMS-10 rubber ABSTRACT: Formulations and technology for making frost-resistant boots which retained their elasticity at -50C were worked out and introduced commercially. Formulations for all parts except the tricot-backed boot tops were based on frost resistant rubber SKMS-10, and natural rubber was used in formulation for fabric application. The antifreeze effectiveness of dibutylphthalate, dibutylsebacinate, MVP oil, "plasticizer" oil and transformer oil was evaluated. The first two compounds gave the best  $\underline{\text{frost-resistance}}^{b}$  at -50 C , and formulations containing dibutylphthalate had the greatest resistance to aging and became brittle below Card 1/2

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-65C. Different type Manufacturing technol boots is analgous to the	ogy for making at for making	ordinary mold	ed boots. Ori	g. art. ha	s: 2
tables ASSOCIATION: Naucl (Scientific Research I	nno-issledovat	el'skiy institut	rezinovykh i l Products); Z	ateksnykh avod <b>"K</b> rasr	izdeli; 1yy
bogatyr'" (Krasnyy Bo	gatyr' Plant)		4	•	
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